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Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. MI22-2343	SERIAL NO. 10/607,869		
<p style="text-align: center;"><b>LIST OF ART CITED BY APPLICANT</b> (Use several sheets if necessary)</p> <p style="text-align: center;">JUL 15 2004</p> <p style="text-align: center;">U.S. PATENT &amp; TRADEMARK OFFICE</p>				APPLICANT: Zhongze Wang			
				FILING DATE 06/27/2003	GROUP 2812		
U.S. PATENT DOCUMENTS							
*Examiner's Initials		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
<i>JL</i>	AA	6,512,244 B1	01/2003	Ju et al.	257	59	
<i>JL</i>	AB	6,509,613 B1	01/2003	En et al.	257	349	
<i>JL</i>	AC	6,541,861 B2	04/2003	Higashi et al.	257	751	
<i>JL</i>	AD	6,680,243 B1	01/2004	Kamath et al.	438	526	
<i>JL</i>	AE	6,531,375 B1	03/2003	Giewont et al.	438	407	
<i>JL</i>	AF	5,773,355	06/1998	Inoue et al.	438	459	
<i>JL</i>	AG	5,767,020	06/1998	Sakaguchi et al.	438	705	
<i>JL</i>	AH	6,534,380 B1	03/2003	Yamauchi et al.	438	455	
<i>JL</i>	AI	5,374,329	12/1994	Miyawaki	156	630	
FOREIGN PATENT DOCUMENTS							
		Document Number	Date	Country	Class	Subclass	Translation
	AJ						Yes
	AK						No
	AL						
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
AM							
AN							
AO							
EXAMINER	DATE CONSIDERED						
<i>Jennifer M. Kennedy November 21, 2004</i>							
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

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QY	AA	2002/0011670 A1	01/2002	Higashi et al.		257	751		
	AB								
	AC								
	AD								
	AE								
	AF								
	AG								
	AH								
	AI								
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